

TYPES 2N5949 THRU 2N5953 N-CANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

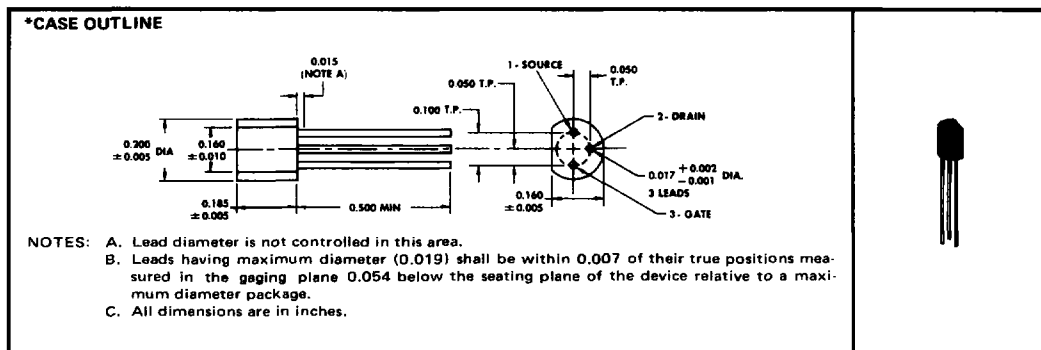
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SILECT† FIELD-EFFECT TRANSISTORS‡

- Narrow I_{DSS} and $V_{GS(off)}$ Ranges
- For Low-Noise Audio-Frequency Amplifier Applications
- For RF Amplifier Applications Thru 100 MHz
- Low $r_{ds(on)}$ for Chopper and Switching Applications

mechanical data

These transistors are encapsulated in a plastic compound specifically designed for this purpose, using a highly mechanized process developed by Texas Instruments. The case will withstand soldering temperatures without deformation. These devices exhibit stable characteristics under high-humidity conditions and are capable of meeting MIL-STD-202C Method 106B. The transistors are insensitive to light.



*absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

Drain-Gate Voltage	30 V
Reverse Gate-Source Voltage	-30 V
Continuous Forward Gate Current	10 mA
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 1)	360 mW
Continuous Device Dissipation at (or below) 25°C Lead Temperature (See Note 2)	500 mW
Storage Temperature Range	-65°C to 150°C
Lead Temperature 1/16 Inch from Case for 10 Seconds	260°C

- NOTES: 1. Derate linearly to 150°C free-air temperature at the rate of 2.88 mW/°C.
2. Derate linearly to 150°C lead temperature at the rate of 4 mW/°C. Lead temperature is measured on the gate lead 1/16 inch from the case.

*JEDEC registered data. This data sheet contains all applicable registered data in effect at the time of publication.

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‡U. S. Patent No. 3,439,238

USES CHIP JN51

TYPES 2N5949 THRU 2N5953 N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	2N5949		2N5950		2N5951		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
V(BR)GSS Gate-Source Breakdown Voltage	I _G = -1 μA, V _{DS} = 0	-30		-30		-30		V
I _{GSS} Gate Reverse Current	V _{GS} = -15 V, V _{DS} = 0 V _{GS} = -15 V, V _{DS} = 0, T _A = 100°C		-1		-1		-1	nA
V _{GS(off)} Gate-Source Cutoff Voltage	V _{DS} = 15 V, I _D = 100 nA	-3	-7	-2.5	-6	-2	-5	V
V _{GS} Gate-Source Voltage	V _{DS} = 15 V, I _D = 1.2 mA V _{DS} = 15 V, I _D = 1 mA V _{DS} = 15 V, I _D = 0.7 mA	-2.25	-6	-1.8	-5			V
I _{DSS} Zero-Gate-Voltage Drain Current	V _{DS} = 15 V, V _{GS} = 0, See Note 3	12	18	10	15	7	13	mA
r _{ds(on)} Small-Signal Drain-Source On-State Resistance	V _{GS} = 0, I _D = 0, f = 1 kHz		200		210		250	Ω
y _{fs} Small-Signal Common-Source Forward Transfer Admittance	V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz, See Note 4	3.5	7.5	3.5	7.5	3.5	6.5	mmho
y _{os} Small-Signal Common-Source Output Admittance			75		75		75	μmho
C _{iss} Common-Source Short-Circuit Input Capacitance	V _{DS} = 15 V, V _{GS} = 0, f = 1 MHz, See Note 4		6		6		6	pF
C _{rss} Common-Source Short-Circuit Reverse Transfer Capacitance			2		2		2	pF
g _{is} Small-Signal Common-Source Input Conductance			250		250		250	μmho
g _{fs} Small-Signal Common-Source Forward Transfer Conductance	V _{DS} = 15 V, V _{GS} = 0, f = 100 MHz, See Note 4	3	7.5	3	7.5	3	6.5	mmho
g _{os} Small-Signal Common-Source Output Conductance			150		125		100	μmho

PARAMETER	TEST CONDITIONS	2N5952		2N5953		UNIT	
		MIN	MAX	MIN	MAX		
V(BR)GSS Gate-Source Breakdown Voltage	I _G = -1 μA, V _{DS} = 0		-30		-30	V	
I _{GSS} Gate Reverse Current	V _{GS} = -15 V, V _{DS} = 0 V _{GS} = -15 V, V _{DS} = 0, T _A = 100°C			-1	-1	nA	
V _{GS(off)} Gate-Source Cutoff Voltage	V _{DS} = 15 V, I _D = 100 nA			-1.3	-3.5	-3	V
V _{GS} Gate-Source Voltage	V _{DS} = 15 V, I _D = 0.4 mA V _{DS} = 15 V, I _D = 0.25 mA			-0.75	-3		V
I _{DSS} Zero-Gate-Voltage Drain Current	V _{DS} = 15 V, V _{GS} = 0, See Note 3		4	8	2.5	5	mA
r _{ds(on)} Small-Signal Drain-Source On-State Resistance	V _{GS} = 0, I _D = 0, f = 1 kHz				300	375	Ω
y _{fs} Small-Signal Common-Source Forward Transfer Admittance	V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz, See Note 4		2	6.5	2	6.5	mmho
y _{os} Small-Signal Common-Source Output Admittance					50	50	μmho
C _{iss} Common-Source Short-Circuit Input Capacitance	V _{DS} = 15 V, V _{GS} = 0, f = 1 MHz, See Note 4				6	6	pF
C _{rss} Common-Source Short-Circuit Reverse Transfer Capacitance					2	2	pF
g _{is} Small-Signal Common-Source Input Conductance					250	250	μmho
g _{fs} Small-Signal Common-Source Forward Transfer Conductance	V _{DS} = 15 V, V _{GS} = 0, f = 100 MHz, See Note 4		1	6.5	1	6.5	mmho
g _{os} Small-Signal Common-Source Output Conductance					75	50	μmho

*operating characteristics at 25°C free-air temperature

PARAMETER	TEST CONDITIONS	ALL TYPES		UNIT
		MIN	MAX	
F Common-Source Spot Noise Figure	V _{DS} = 15 V, V _{GS} = 0, f = 100 MHz, R _G = 1 kΩ, See Note 4 V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz, R _G = 1 MΩ, See Note 4		5	dB
V _n Equivalent Input Noise Voltage	V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz, See Note 4		100	nV/√Hz

NOTES: 3. This parameter must be measured using pulse techniques. t_w = 300 μs, duty cycle ≤ 2%.

4. These parameters must be measured with bias conditions applied for less than 5 seconds to avoid overheating.

*JEDEC registered data